# A3V26S004N Airfast RF Power LDMOS Transistor

Rev. 0 — December 2020

This 26 dBm RF power LDMOS transistor is designed for cellular base station applications covering the frequency range of 2496 to 2690 MHz.

#### 2600 MHz

• Typical Single-Carrier W-CDMA Reference Circuit Performance:  $V_{DD}$  = 42 Vdc,  $I_{DQ}$  = 17 mA,  $P_{out}$  = 23.5 dBm Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF.<sup>(1)</sup>

Frequency	G <sub>ps</sub> (dB)	η <sub>D</sub> (%)	Output PAR (dB)	ACPR (dBc)
2515 MHz	23.2	15.1	10.3	-35.0
2595 MHz	23.0	15.5	9.6	-37.0
2675 MHz	22.0	14.8	9.3	-37.7

1. All data measured in reference circuit with device soldered to printed circuit board.

#### Features

- · Designed for low complexity analog or digital linearization systems
- Universal broadband driver
- · Optimized for massive MIMO active antenna systems for 5G base stations



Data Sheet: Technical Data

Figure 1. Pin Connections



#### Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V <sub>DSS</sub>	-0.5, +105	Vdc
Gate-Source Voltage	V <sub>GS</sub>	-6.0, +10	Vdc
Operating Voltage	V <sub>DD</sub>	55, +0	Vdc
Storage Temperature Range	T <sub>stg</sub>	–65 to +150	°C
Case Operating Temperature Range	T <sub>C</sub>	-40 to +150	°C
Operating Junction Temperature Range (1,2)	TJ	-40 to +225	°C

### **Table 2. Thermal Characteristics**

Characteristic	Symbol	Value <sup>(2,3)</sup>	Unit
Thermal Resistance, Junction to Case Case Temperature 125°C, 26.0 dBm Avg., W-CDMA, 48 Vdc, I <sub>DQ</sub> = 17 mA, 2595 MHz	R <sub>θJC</sub>	8.0	°C/W

#### **Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JS-001-2017)	1C
Charge Device Model (per JS-002-2014)	C2a

#### Table 4. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD22-A113, IPC/JEDEC J-STD-020		260	°C

## Table 5. Electrical Characteristics (T<sub>A</sub> = $25^{\circ}$ C unless otherwise noted)

Characteristic		Min	Тур	Max	Unit
Off Characteristics					
Zero Gate Voltage Drain Leakage Current (V <sub>DS</sub> = 105 Vdc, V <sub>GS</sub> = 0 Vdc)	I <sub>DSS</sub>			10	μAdc
Zero Gate Voltage Drain Leakage Current $(V_{DS} = 55 \text{ Vdc}, V_{GS} = 0 \text{ Vdc})$	I <sub>DSS</sub>	_	_	1	μAdc
Gate-Source Leakage Current (V <sub>GS</sub> = 8 Vdc, V <sub>DS</sub> = 0 Vdc)	I <sub>GSS</sub>			1	μAdc
On Characteristics					
Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 10 \mu \text{Adc})$	V <sub>GS(th)</sub>	0.7	1.2	1.7	Vdc
Gate Quiescent Voltage $(V_{DD} = 48 \text{ Vdc}, I_D = 16 \text{ mAdc}, \text{Measured in Functional Test})$	V <sub>GS(Q)</sub>	1.6	1.78	1.9	Vdc

1. Continuous use at maximum temperature will affect MTTF.

2. MTTF calculator available at http://www.nxp.com.

3. Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.

V<sub>DS(on)</sub>

0.2

0.6

0.9

(continued)

Vdc

Drain-Source On-Voltage

 $(V_{GS} = 10 \text{ Vdc}, I_D = 75 \text{ mAdc})$ 

### Table 5. Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted) (continued)

Characteristic	Symbol	Min	Тур	Мах	Unit
<b>Functional Tests</b> <sup>(1)</sup> (In NXP Production Test Fixture, 50 ohm system) $V_{L}$ -tone CW.	<sub>DD</sub> = 48 Vdc, I <sub>D</sub>	<sub>0Q</sub> = 16 mA, P	P <sub>out</sub> = 26 dBm	Avg., f = 269	0 MHz,
Power Gain	G <sub>ps</sub>	19.5	23.3	26.0	dB
Drain Efficiency	η <sub>D</sub>	18.0	21.9	_	%
Pout @ 6 dB Compression Point	P6dB	33.5	35.0	_	dBm
<b>Videband Ruggedness</b> (In NXP Reference Circuit, 50 ohm system) I <sub>DQ</sub> <i>v</i> ith 10 dB PAR	= 17 mA, f = 2	595 MHz, Ad	ditive White G	aussian Nois	e (AWGN)
ISBW of 400 MHz at 55 Vdc, 1.5 W Avg. Modulated Output Power (3 dB Input Overdrive from 0.7 W Avg. Modulated Output Power)	No Device Degradation				
ypical Performance <sup>(2)</sup> (In NXP Reference Circuit, 50 ohm system) V <sub>DE</sub>	= 42 Vdc, I <sub>DQ</sub>	e = 17 mA, 25	15–2675 MHz	Bandwidth	
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW <sub>res</sub>		170	—	MHz
Gain Flatness in 160 MHz Bandwidth @ P <sub>out</sub> = 23.5 dBm Avg.	G <sub>F</sub>	—	0.7	_	dB
Fast CW, 27 ms Sweep		1			1
Pout @ 3 dB Compression Point	P3dB	_	3.1	_	W
AM/PM (Maximum value measured at the P3dB compression point across the 2515–2675 MHz bandwidth)	Φ		-23	—	0
Gain Variation over Temperature (-40°C to +85°C)	ΔG		0.017	_	dB/°C
Output Power Variation over Temperature (-40°C to +85°C)	∆P1dB	_	0.004	—	dB/°C

### Table 6. Ordering Information

Device	Tape and Reel Information	Package
A3V26S004NT6	T6 Suffix = 5,000 Units, 12 mm Tape Width, 13-inch Reel	DFN 4.5 × 4

1. Part internally input matched.

2. All data measured in fixture with device soldered to printed circuit board.

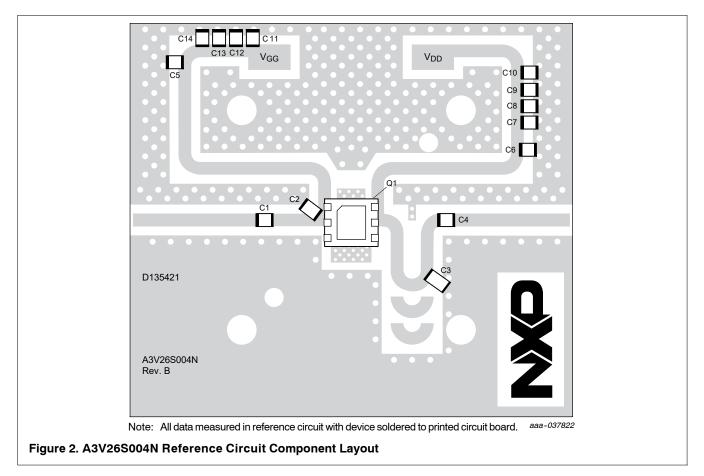


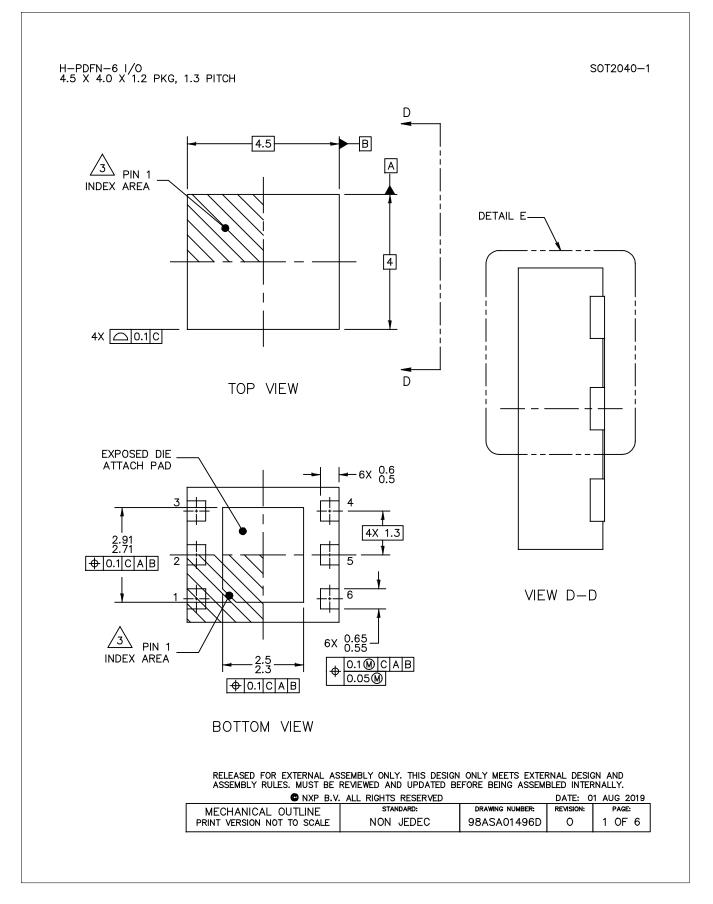
Table 7. A3V26S004N Reference Circuit C	Component Designations and Values

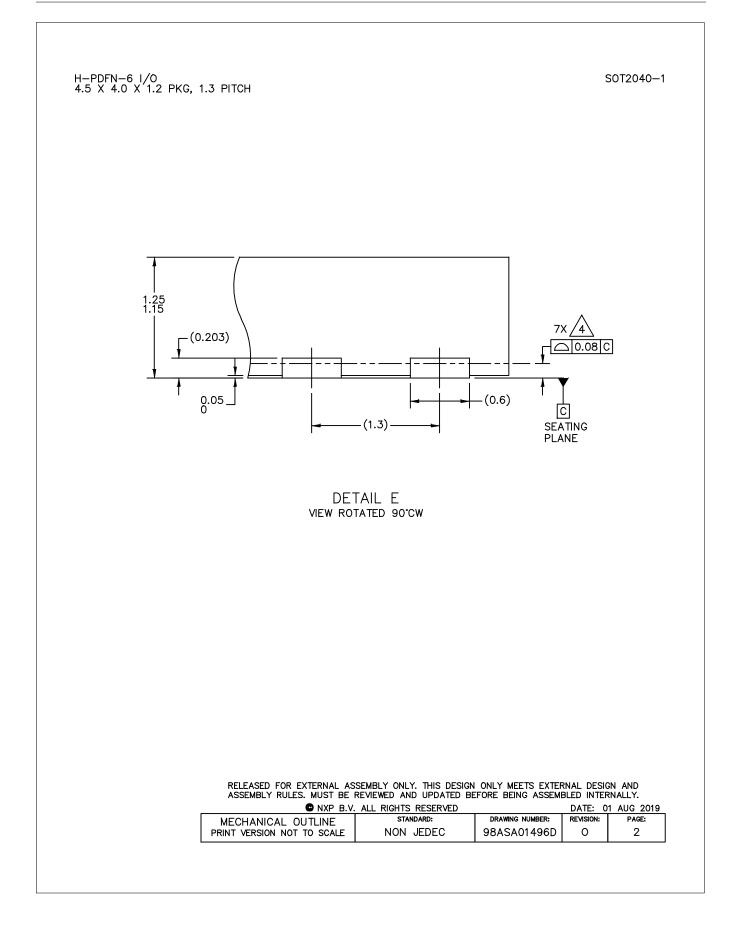
Part	Description	Part Number	Manufacturer
C1	6.8 pF Chip Capacitor	600F6R8BW250XT	ATC
C2	1.0 pF Chip Capacitor	600F1R0BW250XT	ATC
C3	1.8 pF Chip Capacitor	600F1R8BW250XT	ATC
C4	10 pF Chip Capacitor	600F100FW250XT	ATC
C5, C6	20 pF Chip Capacitor	600F200FW250XT	ATC
C7	0.1 μF Chip Capacitor	GRM319R71H104KA	Murata
C8	1 μF Chip Capacitor	GRM32ER72A105KA	Murata
C9, C10	10 μF Chip Capacitor	GRM31CR61H106KA	Murata
C11	10 μF Chip Capacitor	GRM21BR61C106KE	Murata
C12	1 μF Chip Capacitor	08055C105KAT2A	AVX
C13	0.1 μF Chip Capacitor	GRM188R71H104KA	Murata
C14	2.2 nF Chip Capacitor	GRM1885C1H222JA	Murata
Q1	RF Power LDMOS Transistor	A3V26S004N	NXP
PCB	Rogers RO4350B, 0.020″, ε <sub>r</sub> = 3.66	D135421	MTL

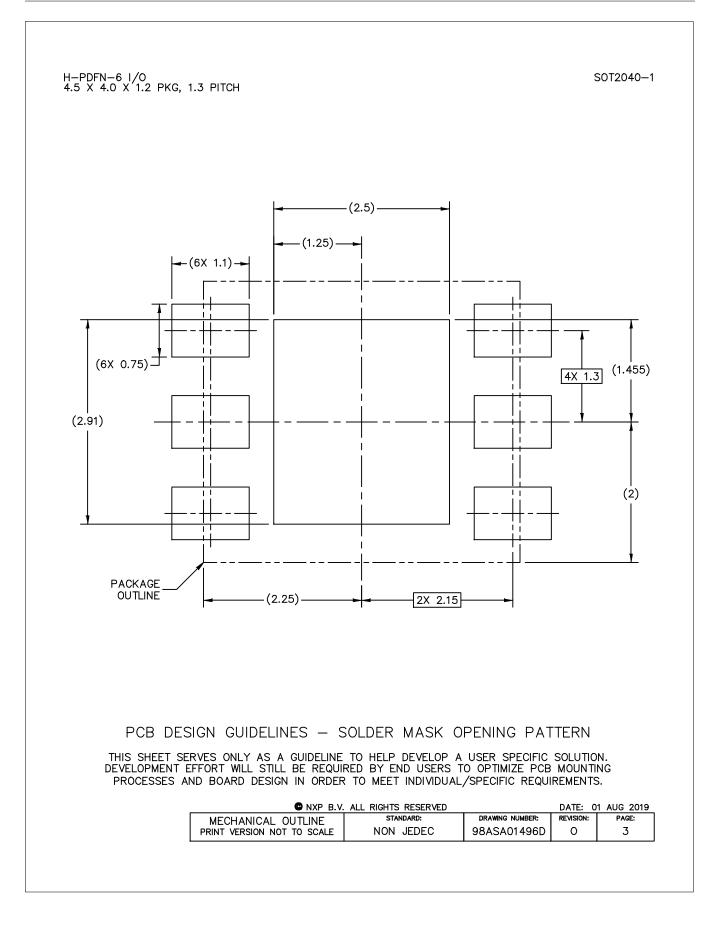


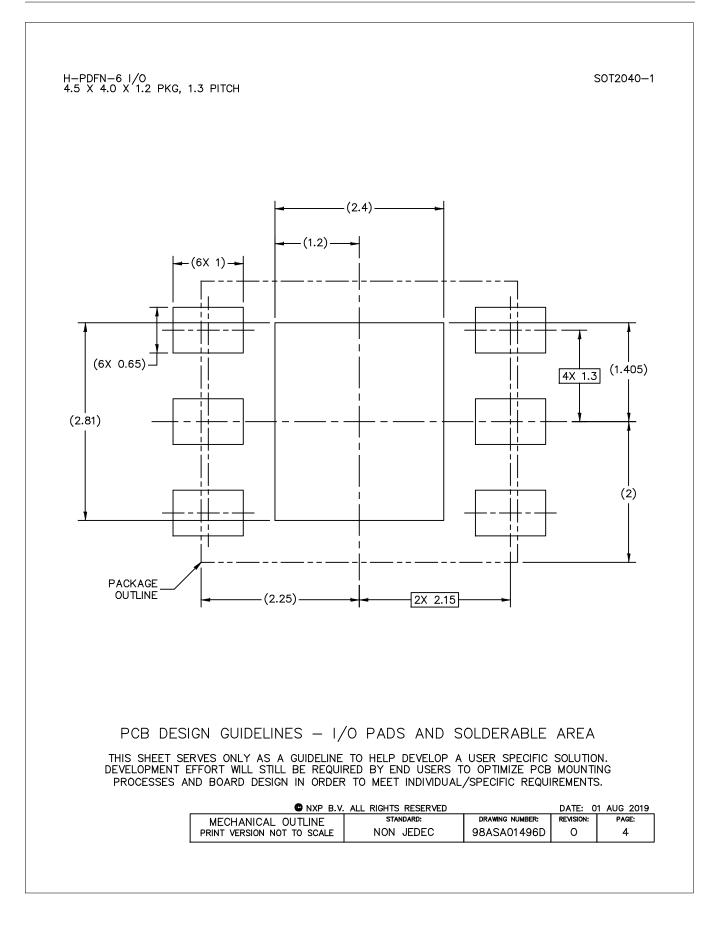
Figure 3. Product Marking

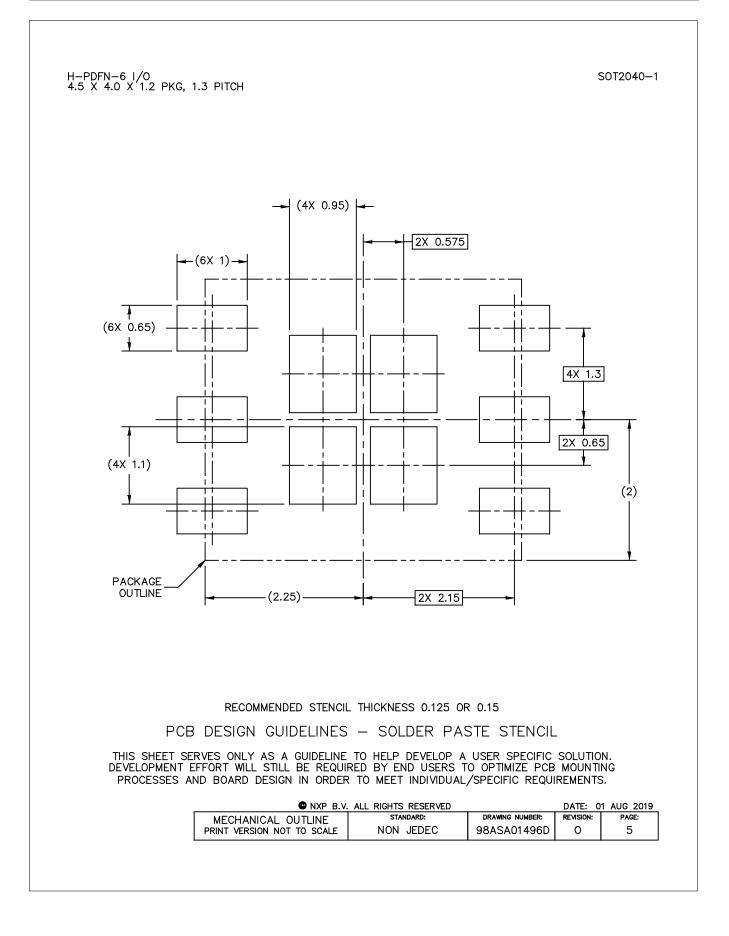
# **Package Information**











H-PDFN-6 I/O 4.5 X 4.0 X 1.2 PKG, 1.3 PITCH

NOTES:

- 1. ALL DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.

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A3V26S004N Airfast RF Power LDMOS Transistor, Rev. 0, December 2020

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# **Product Documentation, Software and Tools**

Refer to the following resources to aid your design process.

### **Application Notes**

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

#### Software

- Electromigration MTTF Calculator
- .s2p File

#### **Development Tools**

Printed Circuit Boards

# **Revision History**

The following table summarizes revisions to this document.

Revision	Date	Description
0	Dec. 2020	Initial release of data sheet

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